International Rectifier

IRF7832PbF

HEXFET® Power MOSFET

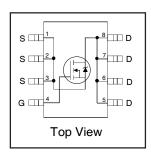
Applications

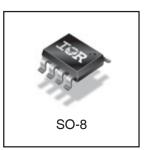
- Synchronous MOSFET for Notebook Processor Power
- Synchronous Rectifier MOSFET for Isolated DC-DC Converters in Networking Systems
- Lead-Free

Benefits

- Very Low R_{DS(on)} at 4.5V V_{GS}
- Ultra-Low Gate Impedance
- Fully Characterized Avalanche Voltage and Current
- 20V V_{GS} Max. Gate Rating
- 100% tested for Rg

V_{DSS}	R _{DS(on)} max	Qg		
30V	4.0 m Ω @ $V_{GS} = 10V$	34nC		





Absolute Maximum Ratings

	Parameter	Max.	Units	
V _{DS}	Drain-to-Source Voltage	30	V	
V_{GS}	Gate-to-Source Voltage	± 20		
I _D @ T _A = 25°C	Continuous Drain Current, V _{GS} @ 10V	20		
I _D @ T _A = 70°C	Continuous Drain Current, V _{GS} @ 10V	16	Α	
I _{DM}	Pulsed Drain Current ①	160		
P _D @T _A = 25°C	Power Dissipation	2.5	W	
P _D @T _A = 70°C	Power Dissipation	1.6	\exists	
	Linear Derating Factor	0.02	W/°C	
TJ	Operating Junction and	-55 to + 155	°C	
T _{STG}	Storage Temperature Range			

Thermal Resistance

	Parameter	Тур.	Max.	Units
$R_{\theta JL}$	Junction-to-Drain Lead		20	°C/W
$R_{\theta JA}$	Junction-to-Ambient ⊕		50	



Static @ T_J = 25°C (unless otherwise specified)

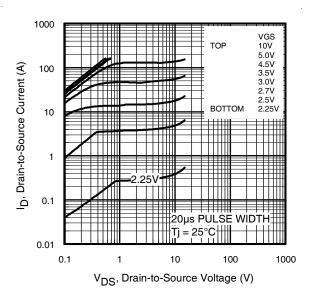
	Parameter	Min.	Тур.	Max.	Units	Conditions
BV _{DSS}	Drain-to-Source Breakdown Voltage	30			٧	$V_{GS} = 0V, I_D = 250\mu A$
$\Delta \mathrm{BV}_{\mathrm{DSS}}/\Delta \mathrm{T}_{\mathrm{J}}$	Breakdown Voltage Temp. Coefficient		0.023		V/°C	Reference to 25°C, I _D = 1mA
R _{DS(on)}	Static Drain-to-Source On-Resistance		3.1	4.0	mΩ	V _{GS} = 10V, I _D = 20A ③
			3.7	4.8	Ī	V _{GS} = 4.5V, I _D = 16A ③
$V_{GS(th)}$	Gate Threshold Voltage	1.39		2.32	٧	$V_{DS} = V_{GS}$, $I_D = 250\mu A$
$\Delta V_{GS(th)}$	Gate Threshold Voltage Coefficient		5.7		mV/°C	
I _{DSS}	Drain-to-Source Leakage Current			1.0	μΑ	$V_{DS} = 24V, V_{GS} = 0V$
				150		$V_{DS} = 24V, V_{GS} = 0V, T_{J} = 125^{\circ}C$
I _{GSS}	Gate-to-Source Forward Leakage			100	nA	$V_{GS} = 20V$
	Gate-to-Source Reverse Leakage			-100	Ī	V _{GS} = -20V
gfs	Forward Transconductance	77			S	V _{DS} = 15V, I _D = 16A
Q_g	Total Gate Charge		34	51		
Q _{gs1}	Pre-Vth Gate-to-Source Charge		8.6		Ī	$V_{DS} = 15V$
Q _{gs2}	Post-Vth Gate-to-Source Charge		2.9		nC	$V_{GS} = 4.5V$
Q_{gd}	Gate-to-Drain Charge		12		ĺ	I _D = 16A
Q_{godr}	Gate Charge Overdrive		10.5		ĺ	See Fig. 16
Q _{sw}	Switch Charge (Q _{gs2} + Q _{gd})		14.9		ĺ	
Q _{oss}	Output Charge		23		nC	$V_{DS} = 16V, V_{GS} = 0V$
R_g	Gate Resistance		1.2	2.4	Ω	
t _{d(on)}	Turn-On Delay Time		12			$V_{DD} = 15V, V_{GS} = 4.5V$
t _r	Rise Time		6.7		İ	$I_D = 16A$
t _{d(off)}	Turn-Off Delay Time		21		ns	Clamped Inductive Load
t _f	Fall Time		13		Ī	
C _{iss}	Input Capacitance		4310			$V_{GS} = 0V$
C _{oss}	Output Capacitance		990		pF	$V_{DS} = 15V$
C _{rss}	Reverse Transfer Capacitance		450		1	f = 1.0MHz

Avalanche Characteristics

	Parameter	Тур.	Max.	Units
E _{AS}	Single Pulse Avalanche Energy ②		260	mJ
I _{AR}	Avalanche Current ①		16	Α

Diode Characteristics

	Parameter	Min.	Тур.	Max.	Units	Conditions
I _S	Continuous Source Current			3.1		MOSFET symbol
	(Body Diode)				Α	showing the
I _{SM}	Pulsed Source Current	_		160		integral reverse
	(Body Diode) ①					p-n junction diode.
V_{SD}	Diode Forward Voltage			1.0	٧	$T_J = 25$ °C, $I_S = 16A$, $V_{GS} = 0V$ ③
t _{rr}	Reverse Recovery Time		41	62	ns	$T_J = 25$ °C, $I_F = 16A$, $V_{DD} = 10V$
Q_{rr}	Reverse Recovery Charge		39	59	nC	di/dt = 100A/μs ③
t _{on}	Forward Turn-On Time	Intrinsic turn-on time is negligible (turn-on is dominated by LS+LD)				



1000

(V)

TOP

10V

3.5V

3.5V

3.5V

2.7V

2.5V

2.5V

2.5V

2.5V

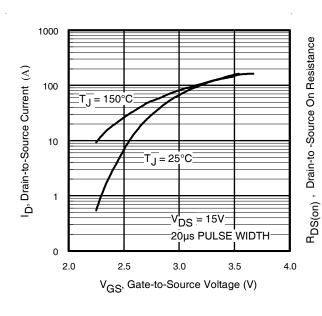
100

100

VDS, Drain-to-Source Voltage (V)

Fig 1. Typical Output Characteristics

Fig 2. Typical Output Characteristics





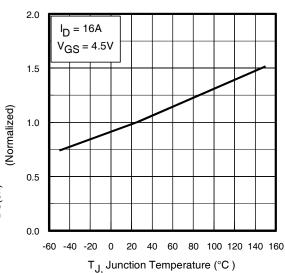


Fig 4. Normalized On-Resistance Vs. Temperature

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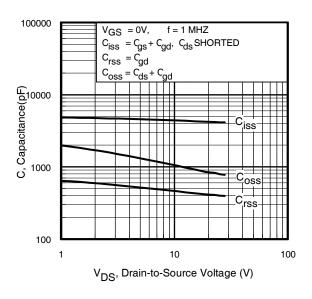


Fig 5. Typical Capacitance Vs. Drain-to-Source Voltage

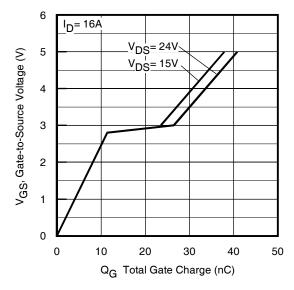


Fig 6. Typical Gate Charge Vs. Gate-to-Source Voltage

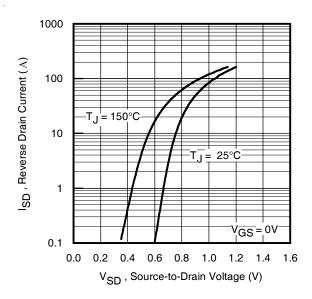


Fig 7. Typical Source-Drain Diode Forward Voltage

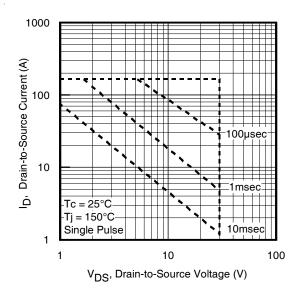
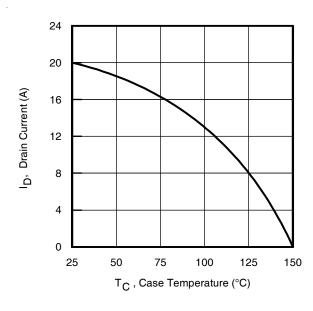


Fig 8. Maximum Safe Operating Area



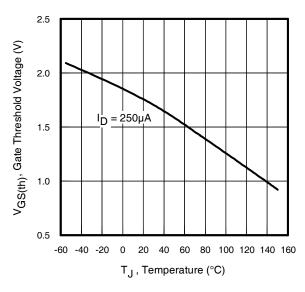


Fig 9. Maximum Drain Current Vs. Case Temperature

Fig 10. Threshold Voltage Vs. Temperature

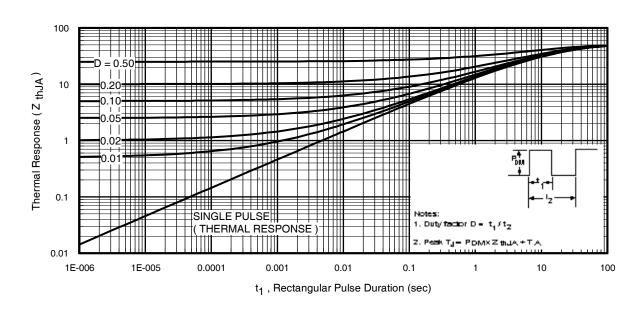


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Ambient

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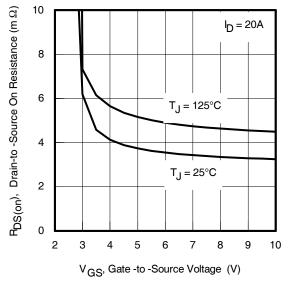


Fig 12. On-Resistance vs. Gate Voltage

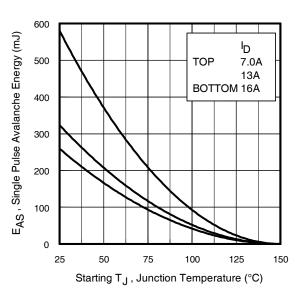


Fig 13. Maximum Avalanche Energy vs. Drain Current

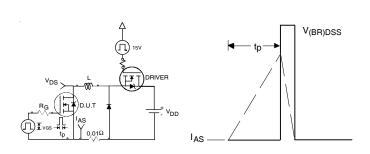


Fig 14. Unclamped Inductive Test Circuit and Waveform

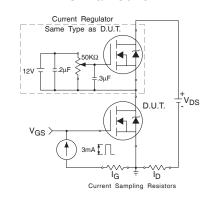


Fig 15. Gate Charge Test Circuit

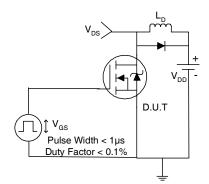


Fig 16. Switching Time Test Circuit

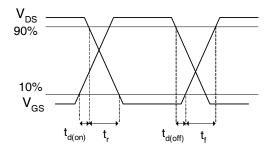


Fig 17. Switching Time Waveforms www.irf.com

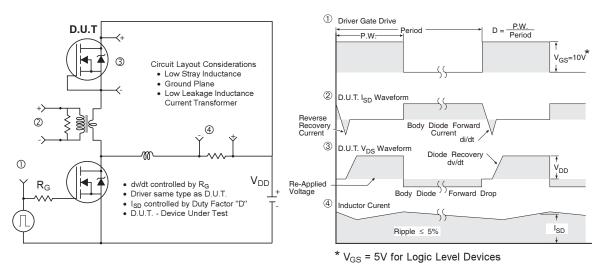


Fig 18. Peak Diode Recovery dv/dt Test Circuit for N-Channel HEXFET® Power MOSFETs

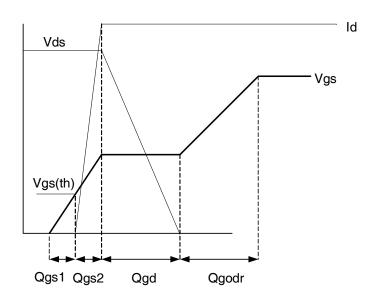


Fig 19. Gate Charge Waveform

Power MOSFET Selection for Non-Isolated DC/DC Converters

Control FET

Special attention has been given to the power losses in the switching elements of the circuit - Q1 and Q2. Power losses in the high side switch Q1, also called the Control FET, are impacted by the $R_{\rm ds(on)}$ of the MOSFET, but these conduction losses are only about one half of the total losses.

Power losses in the control switch Q1 are given by;

$$P_{loss} = P_{conduction} + P_{switching} + P_{drive} + P_{output}$$

This can be expanded and approximated by:

$$\begin{split} P_{loss} &= \left(I_{rms}^{2} \times R_{ds(on)}\right) \\ &+ \left(I \times \frac{Q_{gd}}{i_{g}} \times V_{in} \times f\right) + \left(I \times \frac{Q_{gs2}}{i_{g}} \times V_{in} \times f\right) \\ &+ \left(Q_{g} \times V_{g} \times f\right) \\ &+ \left(\frac{Q_{oss}}{2} \times V_{in} \times f\right) \end{split}$$

This simplified loss equation includes the terms ${\rm Q_{gs2}}$ and ${\rm Q_{oss}}$ which are new to Power MOSFET data sheets.

 Q_{gs2} is a sub element of traditional gate-source charge that is included in all MOSFET data sheets. The importance of splitting this gate-source charge into two sub elements, Q_{gs1} and Q_{gs2} , can be seen from Fig 16.

 Q_{gs2} indicates the charge that must be supplied by the gate driver between the time that the threshold voltage has been reached and the time the drain current rises to I_{dmax} at which time the drain voltage begins to change. Minimizing Q_{gs2} is a critical factor in reducing switching losses in Q1.

 $\rm Q_{oss}$ is the charge that must be supplied to the output capacitance of the MOSFET during every switching cycle. Figure A shows how $\rm Q_{oss}$ is formed by the parallel combination of the voltage dependant (nonlinear) capacitance's $\rm C_{ds}$ and $\rm C_{dg}$ when multiplied by the power supply input buss voltage.

Synchronous FET

The power loss equation for Q2 is approximated by;

$$\begin{aligned} P_{loss} &= P_{conduction} + P_{drive} + P_{output}^* \\ P_{loss} &= \left(I_{rms}^2 \times R_{ds(on)}\right) \\ &+ \left(Q_g \times V_g \times f\right) \\ &+ \left(\frac{Q_{oss}}{2} \times V_{in} \times f\right) + \left(Q_{rr} \times V_{in} \times f\right) \end{aligned}$$

*dissipated primarily in Q1.

For the synchronous MOSFET Q2, $R_{\rm ds(on)}$ is an important characteristic; however, once again the importance of gate charge must not be overlooked since it impacts three critical areas. Under light load the MOSFET must still be turned on and off by the control IC so the gate drive losses become much more significant. Secondly, the output charge $Q_{\rm oss}$ and reverse recovery charge $Q_{\rm rr}$ both generate losses that are transfered to Q1 and increase the dissipation in that device. Thirdly, gate charge will impact the MOSFETs' susceptibility to Cdv/dt turn on.

The drain of Q2 is connected to the switching node of the converter and therefore sees transitions between ground and $V_{\rm in}$. As Q1 turns on and off there is a rate of change of drain voltage dV/dt which is capacitively coupled to the gate of Q2 and can induce a voltage spike on the gate that is sufficient to turn the MOSFET on, resulting in shoot-through current . The ratio of $Q_{\rm gd}/Q_{\rm gs1}$ must be minimized to reduce the potential for Cdv/dt turn on.

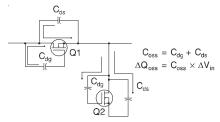


Figure A: Q ... Characteristic

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IRF7832PbF

MILLIMETERS

MAX

1.75

0.51

0.25

5.00

4 00

6.20

0.50

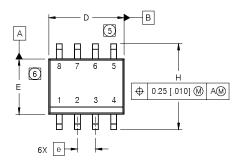
1.27 8°

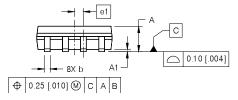
MIN

1.35

0.33

SO-8 Package Details





.0075 .0098 0.19 С D .189 .1968 4.80 Е .1497 .1574 3.80 .050 BASIC 1.27 BASIC е .025 BASIC e 1 0.635 BASIC Н .2284 5.80 Κ .0099 .0196 0.25 L .016 .050 0.40 - K x 45°

INCHES

MAX

.0688

.0098

.020

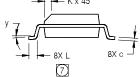
MIN

.0532

Α

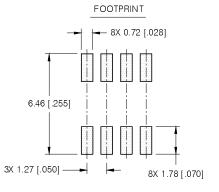
A1 .0040

b 013

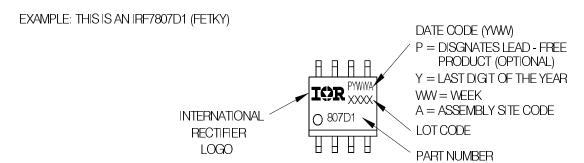


NOTES:

- 1. DIMENSIONING & TOLERANCING PER ASME Y14.5M-1994.
- 2. CONTROLLING DIMENSION: MILLIMETER
- 3. DIMENSIONS ARE SHOWN IN MILLIMETERS [INCHES].
- 4. OUTLINE CONFORMS TO JEDEC OUTLINE MS-012AA.
- (5) DIMENSION DOES NOT INCLUDE MOLD PROTRUSIONS. MOLD PROTRUSIONS NOT TO EXCEED 0.15 [.006].
- (6) DIMENSION DOES NOT INCLUDE MOLD PROTRUSIONS. MOLD PROTRUSIONS NOT TO EXCEED 0.25 [.010].
- (7) DIMENSION IS THE LENGTH OF LEAD FOR SOLDERING TO A SUBSTRATE.

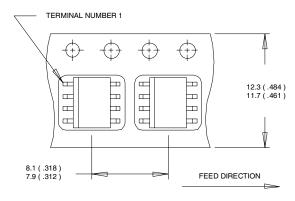


SO-8 Part Marking



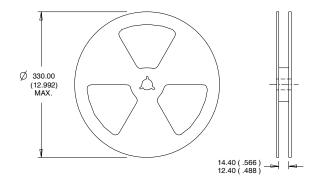
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SO-8 Tape and Reel



NOTES:

- CONTROLLING DIMENSION: MILLIMETER.
 ALL DIMENSIONS ARE SHOWN IN MILLIMETERS(INCHES).
 OUTLINE CONFORMS TO EIA-481 & EIA-541.



- 1. CONTROLLING DIMENSION : MILLIMETER.
- 2. OUTLINE CONFORMS TO EIA-481 & EIA-541.

Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature.
- ② Starting $T_J = 25$ °C, L = 2.0mH, $R_G = 25\Omega$, $I_{AS} = 16$ A.
- ③ Pulse width \leq 400 μ s; duty cycle \leq 2%.
- When mounted on 1 inch square copper board.

Data and specifications subject to change without notice. This product has been designed and qualified for the Consumer market. Qualification Standards can be found on IR's Web site.



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